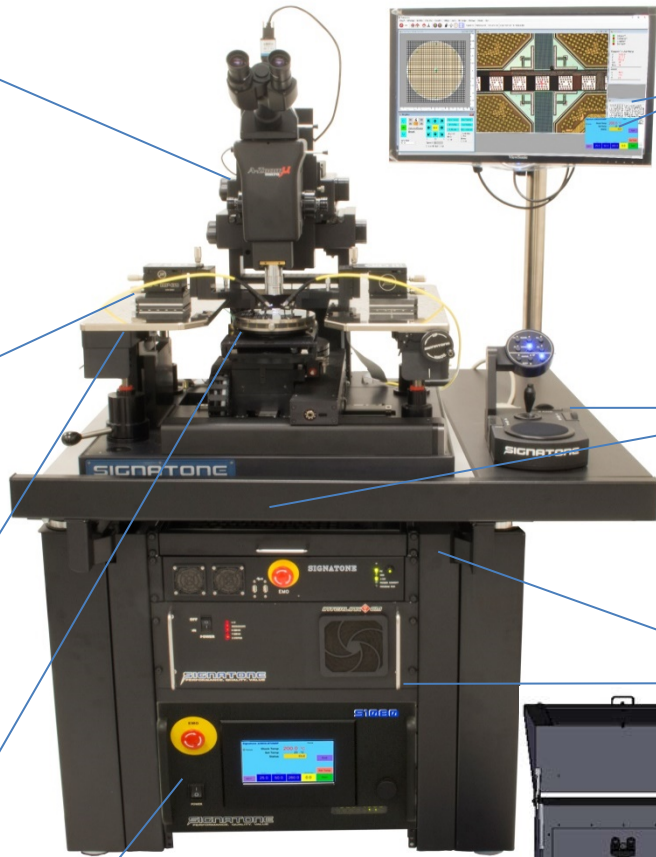


Signatone WL-250 200mm Semi-Automatic Probe System

Performance – Quality – Value - for reliable and accurate RF, DC/CV, and High Power Test Measurements



Microscope and Imaging Options

- Stable microscope bridge
- 50mm x 50mm manual or programmable
- Various optics available
- A-zoom 10:1, or Seiya 12:1 zoom Scopes
- FS70, PSM-100 High Power Microscopes
- Motic and Leica low Power Microscopes
- 5MP Moticam digital or 5MP "Probe-Master" software controlled digital camera.

MicroPositioners and Probes

- Supports 1-4 RF and 1-10 DC Micropositioners.
- A variety of MicroPositioner selections.
- RF Heads (18 -40 GHz, 40-110GHz).
- DC, Coax, Triax, (nA, pA, fA, fF).
- High voltage (3kV TRX, 5kV-12kV COAX), and High Current (up to 100A) probes availed.

Platen

- Large ridged and stable design (12.7mm thick).
- RF positioner mounting holes *
- Water cooled for maximum thermal stability and user safety *
- Supports rectangular probe cards.
- Course and fine lift adjustment for DUT set-up.

Modular Chucks

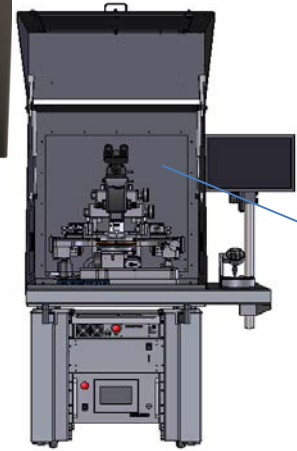
- A variety of ambient or thermal chucks available.
- Standard configuration includes ambient chuck with pin hole vacuum selector zones (5mm-200mm test samples) and Coaxial, Triaxial connections available.
- Selectable range of temperatures +20°C to + 300°C.
- Economically designed for field upgrade.

Thermal Control

- Thermal chucks can be operated by using the fully integrated SW commands on the system control screen or through the rack mounted touch screen display (both Touch-Screen and SW control features are included with S1080 model thermal systems).

--Available Options--

- Second Monitor
- Instruments shelf
- Variety of panels
- Left - right side configurable shelf and monitor mount



Including Dark Box

ProbeMaster Software Suite

- Intuitive and easy to use icon selected commands
- Live video Image for "point & shoot" (move to selected location) and image capture
- Easy Load and wafer alignment
- Precision package allows pattern recognition, auto focus, and "SureTouch" probing features
- Easy to move arrow keys for driving wafer stage, microscope, and 1-4 CAP (Computer Aided Probes)
- Thermal Temperature display and control SW
- GPIB, TC-IP interface for remote control

Joystick and Controls

- Joystick with LED selector panel control of wafer, microscope, and 1-4 CAP probes
- Multi direction proportionate joystick speed control
- Large X-Y-Z thumbwheels with SW adjustable gear ratio for variable speed and. magnifications
- Integrated keyboard and mouse ergonomically located at the front of the system for easy access.

Vibration Isolation Table & Instrument Rack

- System integrated into industry standard high performance isolation table including instrumentation mounting rack, side shelves- single monitor mounts.
- System may be mounted on customer supplied bench or table.

System Dark Box Options

- Test environment for light sensitive measurements
- Mechanically assisted door open and close.
- Multiple panel locations for connectors and cable feed through
- Easy-removable large back panel for system installation and instrumentation integration
- Interlocks for safety and security
- Large front access Door for DUT loading, system reconfiguration and Probe adjustment